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DATE: Wednesday, August 31, 2005

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<input type="checkbox"/>	L5	L3 not L4	382
<input type="checkbox"/>	L4	L2 and porous and anodiz\$6	102
<input type="checkbox"/>	L3	438/404,409.ccls.	457
<input type="checkbox"/>	L2	438/404-412,424-426.ccls.	2956
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<input type="checkbox"/>	L1	porous and anodiz\$6 and ((dielectric with isolation) or SOI) and (via\$1 or trench\$2)	339

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 in All Fields AND in All Fields AND in All Fields**OPTION 2**

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```
porous <and> isolation <and> (anodize <or> anodization <or> anodized)
```



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((porous <and> isolation <and> (anodize <or> anodization <or> anodized))<in>meta

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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

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Article Information

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

- 1. Effective crosstalk Isolation through p⁺ Si substrates with semi-insulating porous Si
Han-Su Kim; Jenkins, K.A.; Ya-Hong Xie;
Electron Device Letters, IEEE
Volume 23, Issue 3, March 2002 Page(s):160 - 162
Digital Object Identifier 10.1109/55.988824
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(201 KB\)](#) IEEE JNL
- 2. FIPOS (Full Isolation by Porous Oxidized Silicon) technology and Its application to LSI's
Imai, K.; Unno, H.;
Electron Devices, IEEE Transactions on
Volume 31, Issue 3, Mar 1984 Page(s):297 - 302
[AbstractPlus](#) | Full Text: [PDF\(752 KB\)](#) IEEE JNL
- 3. The "ISLANDS" method—A manufacturable porous silicon SOI technology
Zorinsky, E.J.; Spratt, D.B.; Virkus, R.L.;
1986 International Electron Devices Meeting
Volume 32, 1986 Page(s):431 - 434
[AbstractPlus](#) | Full Text: [PDF\(688 KB\)](#) IEEE CNF
- 4. Fabrication of a micro-biochemical reactor with thick thermal Isolation layer and integrated I the micro-well
Hoon-Sung Choi; Chang-Taeg Seo; Young-Min Kim; Jang-Kyoo Shin; Pyung Choi; Jong-Hyun Lee
Microprocesses and Nanotechnology Conference, 2003. Digest of Papers. 2003 International
29-31 Oct. 2003 Page(s):326 - 327
[AbstractPlus](#) | Full Text: [PDF\(256 KB\)](#) IEEE CNF
- 5. An LED for silicon-based Integrated optoelectronics
Tsybeskov, L.; Hirschman, K.D.; Duttagupta, S.P.; Fauchet, P.M.;
Device Research Conference, 1996. Digest. 54th Annual
24-26 June 1996 Page(s):150 - 151
Digital Object Identifier 10.1109/DRC.1996.546416
[AbstractPlus](#) | Full Text: [PDF\(148 KB\)](#) IEEE CNF

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